Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/802,544	WANG ET AL.
Examiner	Art Unit
Paul D. Kim	3729

	SEAR	CHED	
Class	Subclass	Date	Examiner
29	603.03- 603.06	11/22/2005	PK
360	264.2 264.7		
	265 266		
	265.7- 265 .9		
	244.5 244.7		
228	175 180.2 <u>2</u>	,	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR	NOTES RCH STRATEGY)
	DATE	EXMR
Reviewed Parent Application 10/098,067 (US PAT. 6,937,443)	11/22/2005	PK
Text Search EAST/NPL (IEEE)	11/22/2005	PK
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